

# RFS-R 3-2

Scanner Probe 30 MHz up to 3 GHz



## Short description

The RFS-R 3-2 scanner probe is used for the high-resolution measurement of RF magnetic fields directly on an assembly e.g. in range around pins and IC cases, conducting paths, decoupling capacitor and EMC components.

The RFS-R 3-2 is a passive near-field probe. The H-field probe is designed to be used very close to the components and where high magnetic field strength occurs. It has a current attenuating sheath and, therefore, is electrically shielded. The magnetic field scanner probe can be connected to a spectrum analyzer or an oscilloscope with a 50 Ω input. The H-field probe does not have an internal terminating resistance of 50 Ω.

## Technical parameters

|                       |                  |
|-----------------------|------------------|
| Frequency range       | 30 MHz ... 3 GHz |
| Resolution            | ≈ 1 mm           |
| Probe head dimensions | Ø ≈ 3 mm         |
| Connector - output    | SMA, male, jack  |

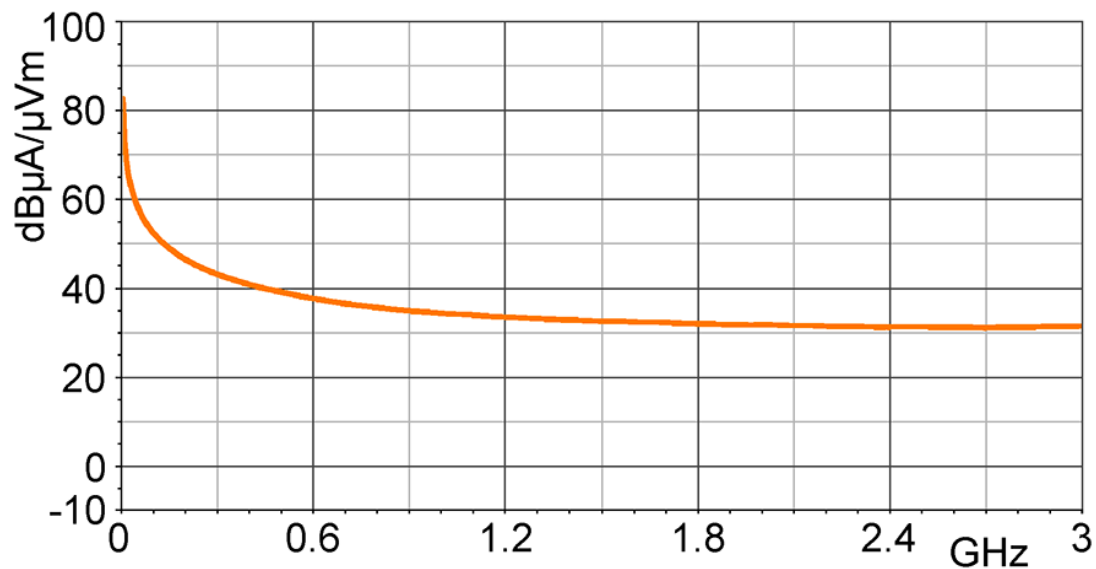
Frequency response [dBμV] / [dBμA/m]



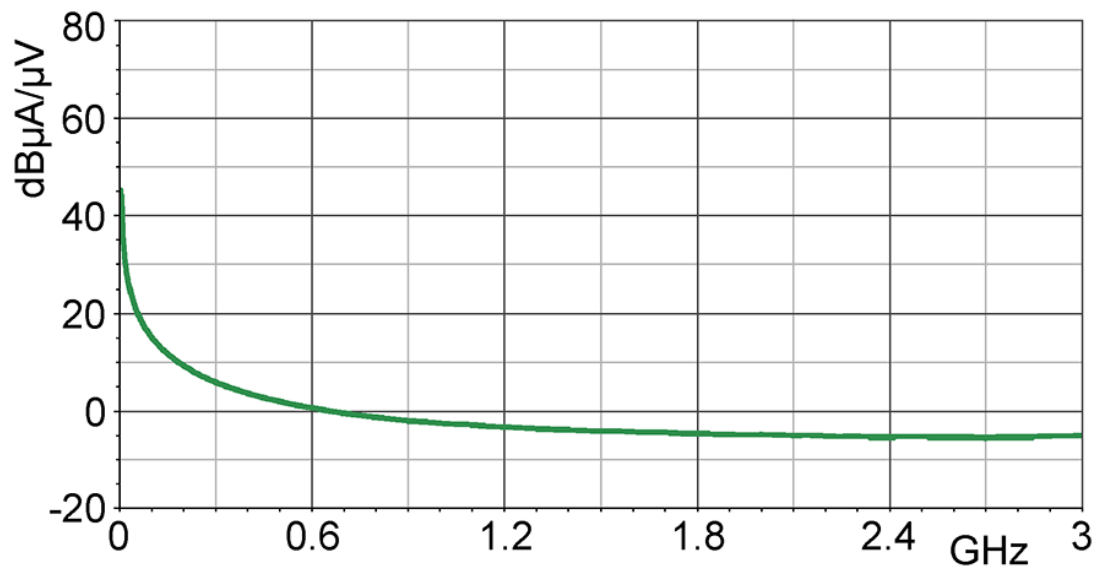
# RFS-R 3-2

Scanner Probe 30 MHz up to 3 GHz

H-field correction curve [dB $\mu$ A/m] / [dB $\mu$ V]



Current correction curve [dB $\mu$ A] / [dB $\mu$ V]



# RFS-R 3-2

Scanner Probe 30 MHz up to 3 GHz

## Measuring principles

